SEM • TEM • SAMPLE PREP • MICROPROBES

JEOL

www.jeolusa.com

See us at Semicon West 2013

July 9 - 11

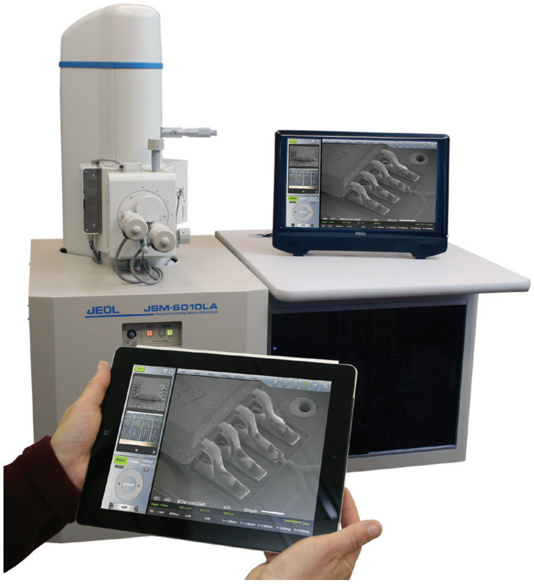
Booth #5646 Moscone Center, San Francisco

Breaking the <1nm Imaging Resolution Barrier in Electron Microscopy

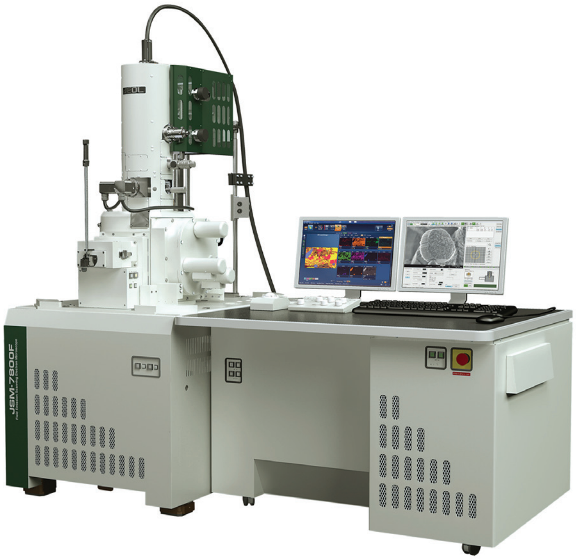
JEOL is renowned worldwide for its ultrahigh resolution electron microscopes for characterization and analysis, sample preparation tools, and unrivaled service and applications support. Now, with its new generation of field emission Scanning Electron Microscopes (SEMs), JEOL offers extreme resolution at the angstrom scale, breaking the <1nm imaging resolution barrier at 1kV with a guaranteed specification of 0.8nm (8A). The JSM-7800F extreme resolution analytical SEM is essentially a nanolaboratory that combines 1,000,000X imaging, x-ray analysis, crystallographic analysis, and cryogenic analysis under one column. Optional cathodoluminescence imaging, nanolithography capability and heating/cooling tensile stages for in situ and thermodynamic experiments expand the utility and performance of this valuable tool.

JEOL's ion beam cross sectioning tool prepares pristine samples for imaging of wirebonds, solar panels, thin films, semiconductor devices, and composites that are easily damaged by traditional chemical or mechanical methods.

JEOL's complete line of SEMs and Transmission Electron Microscopes (TEMs) are helping industry leaders advance leading edge technology and conduct failure analysis and R&D to improve manufacturing processes and yields. JEOL will help you see your most difficult samples in unprecedented detail, with the applications and service support that exceeds expectations of even the most advanced fabs.



InTouchScope SEM



JSM-7800F Field Emission SEM